

**Embedded instrumentation toolbox for screening marginal defects and outliers for production**

**Odintsov, Sergei; Jutman, Artur; Devadze, Sergei; Aleksejev, Igor** IEEE AUTOTESTCON 2017 : Schaumburg, USA, Sept 11-14, 2017 : proceedings 2017 / p. 336-334 : ill <https://doi.org/10.1109/AUTEST.2017.8080516>

**FPGA-based synthetic instrumentation for board test**

**Aleksejev, Igor; Jutman, Artur; Devadze, Sergei; Odintsov, Sergei; Wenzel, Thomas** Proceedings : International Test Conference 2012 2012 / p. 1-10 : ill <https://ieeexplore.ieee.org/document/6401571>

**In-field detection of degradation on PCB assembly high-speed buses**

**Odintsov, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 6 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532547>

**Marginal PCB assembly defect detection on DDR3/4 memory bus**

**Odintsov, Sergei; Jutman, Artur; Devadze, Sergei** 2017 IEEE International Test Conference (ITC 2017) : Forth Worth, Texas, USA, 31 October - 2 November 2017 2017 / p. 238-247 : ill <https://doi.org/10.1109/TEST.2017.8242070> [Conference proceedings at Scopus Article at Scopus Article at WOS](#)

**A new FPGA-based detection method for spurious variations in PCBA power distribution network**

**Odintsov, Sergei; Bozzoli, Ludovica; De Sio, Corrado; Sterpone, Luca; Jutman, Artur** 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/DDECS.2019.8724662>

**Ways for board and system test to benefit from FPGA embedded instrumentation**

**Ehrenberg, Heiko; Odintsov, Sergei; Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Wenzel, Thomas** 2019 IEEE AUTOTESTCON 2019 / 10 p : ill <https://doi.org/10.1109/AUTOTESTCON43700.2019.8961057>